

## CONCURRENT TEST GENERATION

Speaker: **Alok Doshi**

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**ABSTRACT:** We define a new type of test, called “concurrent test,” for a combinational circuit. Given a set of target faults, a concurrent-test is an input vector that detects all (or most) faults in the set. When concurrent tests are generated for fault sets obtained from independence fault collapsing, minimal or near-minimal tests can be expected. This paper gives new simulation-based methods for independence fault collapsing and for deriving concurrent tests using single-fault ATPG.